

Systematic error for CNI polarimeter – take II

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1. Randomized spin bit pattern
2. Effect of bunched/de-bunched
beam on noise correction
3. χ^2/ndf scale factor

Randomized spin bit pattern

Basic idea is to see the distribution of physics asymmetries with forced un-polarized spin bit patterns

Procedure:

from the spin bit pattern

BLUE: 0++--++- ...

For + sign (26bunch)

2nd, 3rd, 6th, 7th ...



half



Half-flip

group1

group2

For – sign (26bunch)

4th, 5th, 8th, 9th ...



half



Half-flip

group3

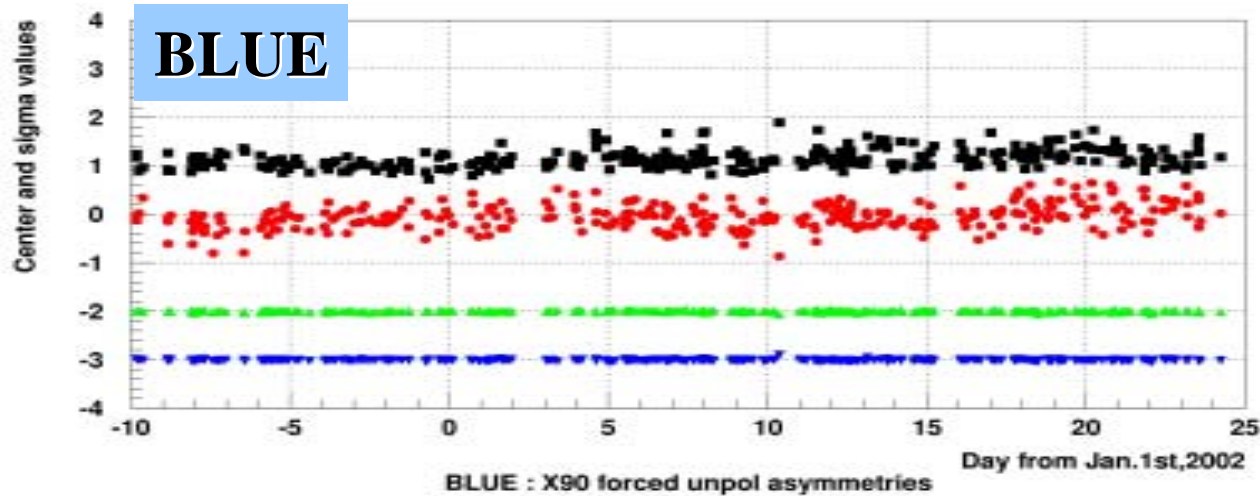
group4

Randomly dividing into two groups, and assign the flipped spin bit for group2 and group4 to force un-polarization

Possible combinations are

$${}_{26}C_{13} * {}_{26}C_{13} = (26!/13!/13!)^2 \sim 1.1 * 10^{14} \text{ combinations}$$

Day plots for significance value ($=\text{asymmetry}/\sigma_{\text{stat}}$)
 10^3 random spin patterns are applied for every run



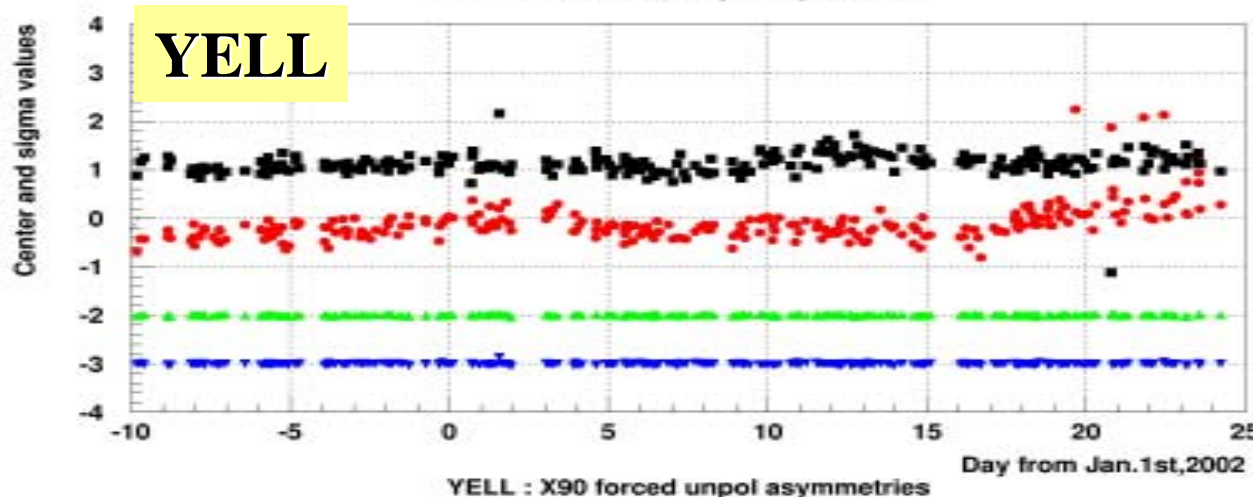
← Sigma(from fit)

← Mean(from fit)

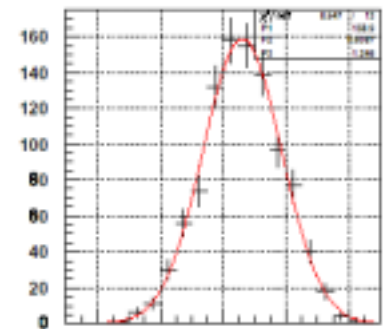
For Consistency check

← (Fit mean – Average mean) -2

← (Sigma – RMS) -3



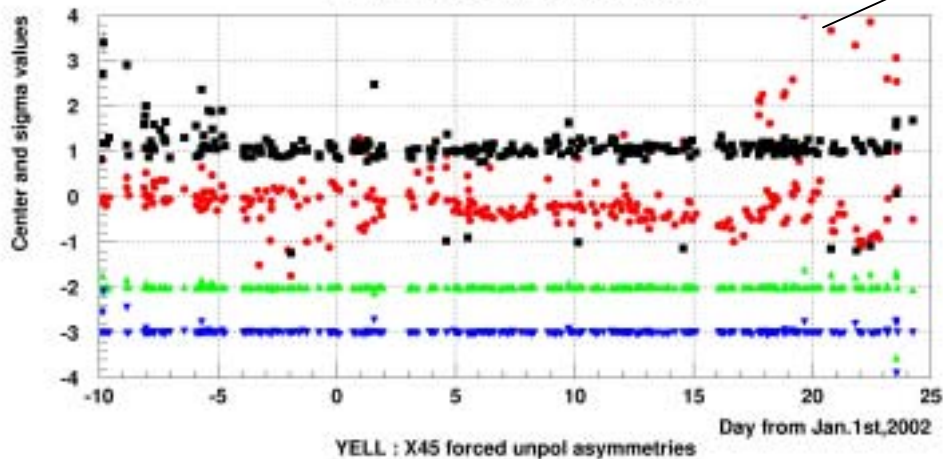
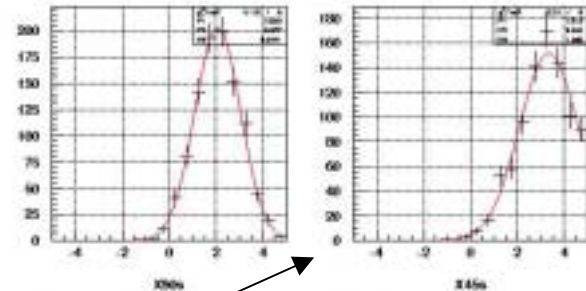
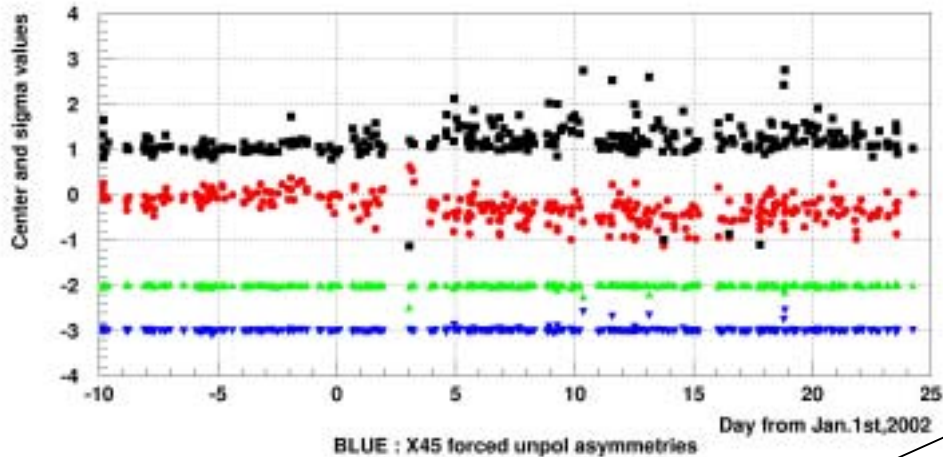
Fit sample run789



X90/sigma

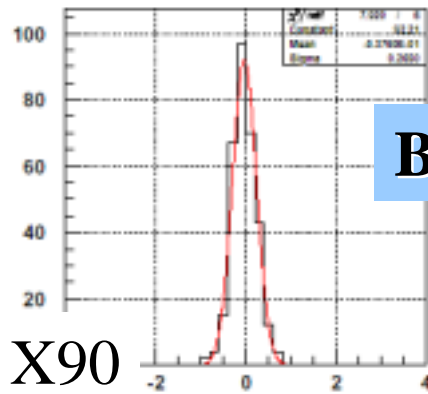
Same plots for X45

Run 873



- Mean > sigma runs are found
- Large false asymmetries are expected for those runs

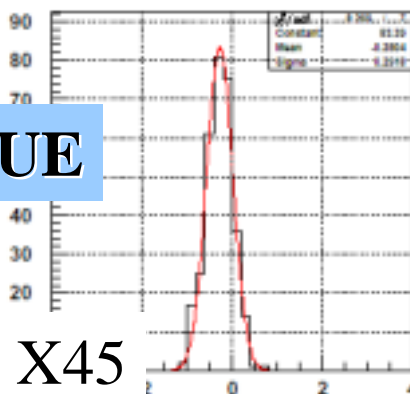
Projection plots



BLUE

X90

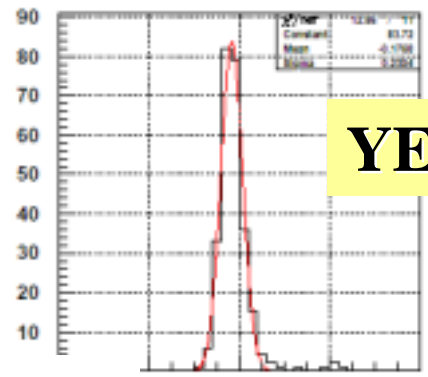
X90 blue mean



X45

X45 blue mean

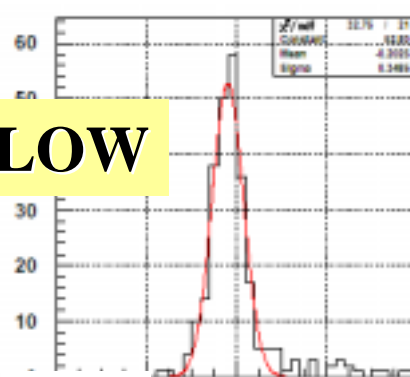
Here the important value is the center of distribution



YELLOW

X90

X90 yell mean



X45

X45 yell mean

BLUE

X90 $\rightarrow -0.04\sigma$

X45 $\rightarrow -0.28\sigma$

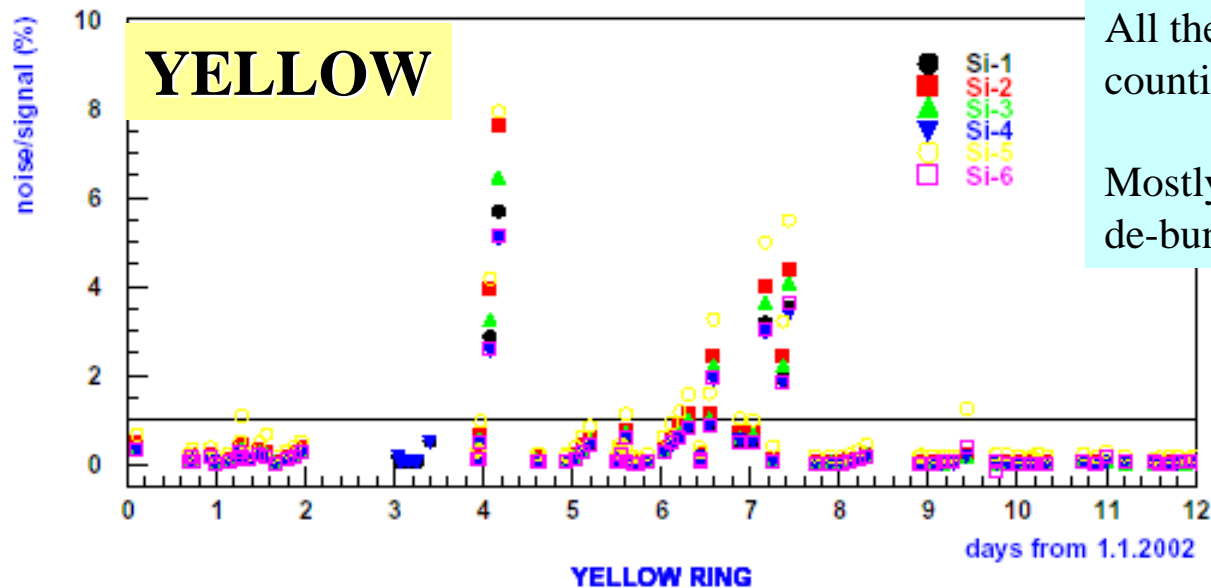
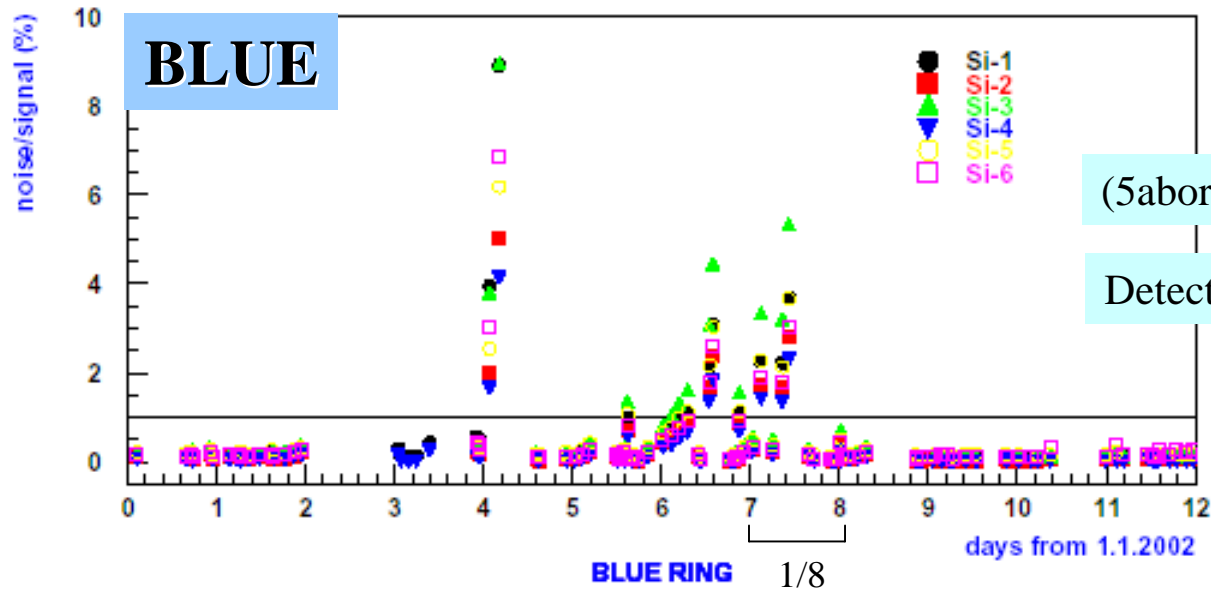
YELLOW

X90 $\rightarrow -0.18\sigma$

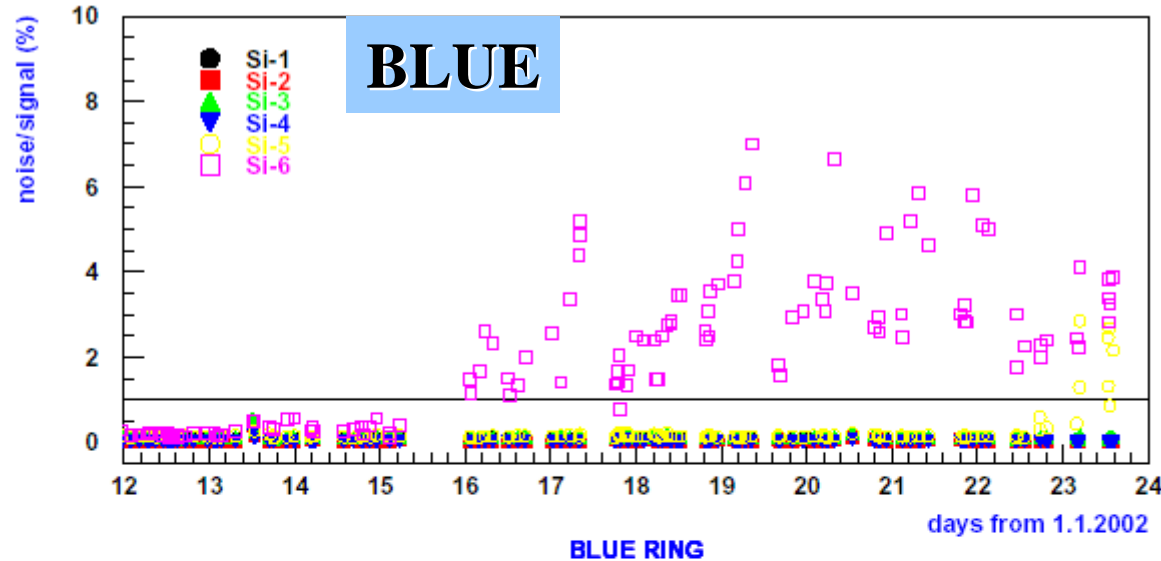
X90 $\rightarrow -0.20\sigma$

Distribution of fit mean from significance plots

De-bunched beam effect seen by CNI

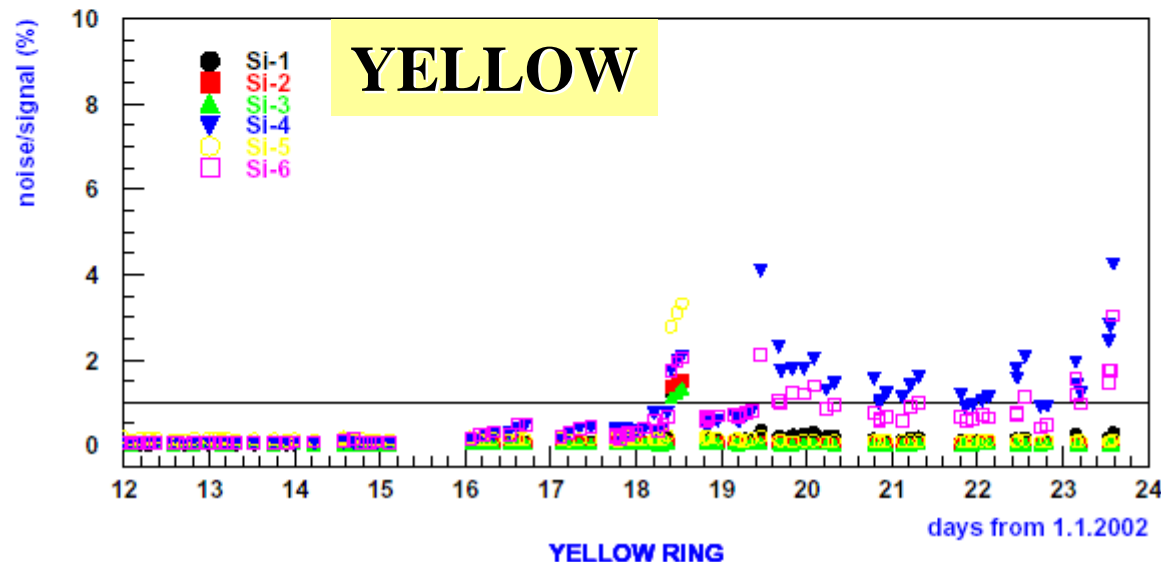


Strip specific noise effect seen by CNI

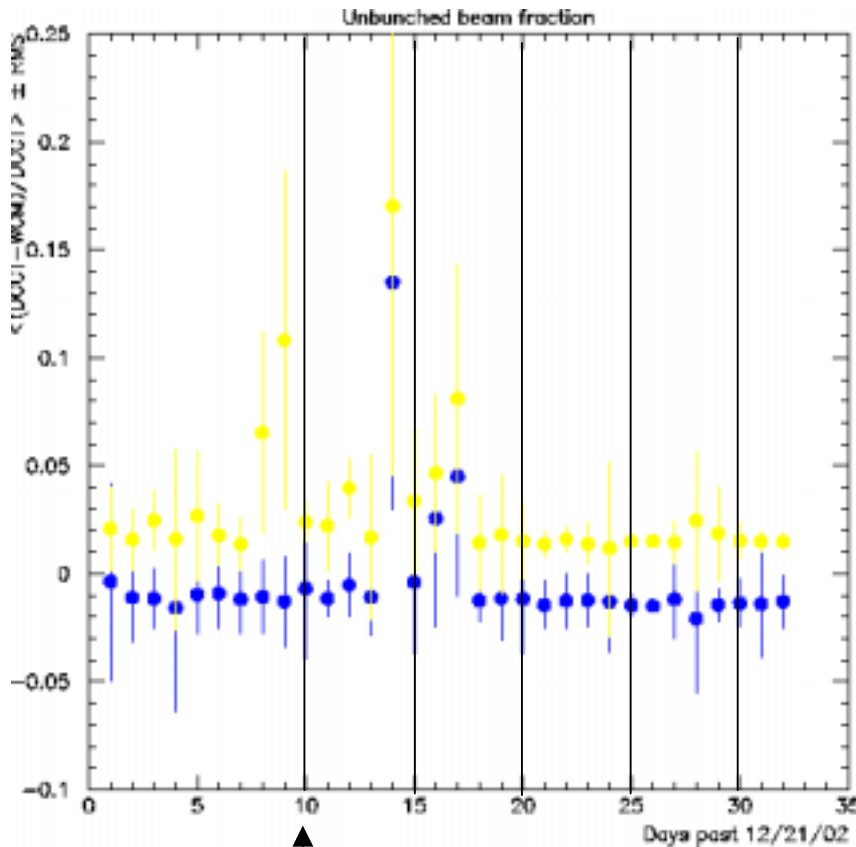


Some strips became largely noisy while the other rest remain silent
→ can be attributed the noise

- The un-bunched component and the noise effects are clearly separated
- Special care must be taken for un



Un-bunched Beam Fraction by L.Bland



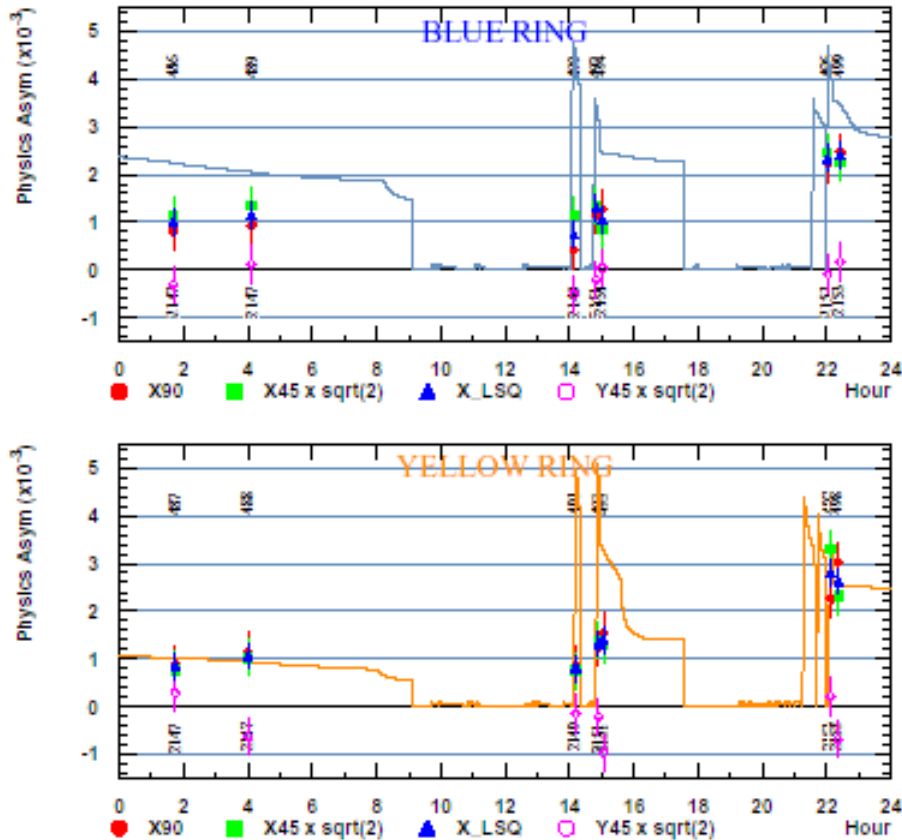
The un-bunched beam fraction from RHIC run 2 is determined for the period from 12/22/01 to 1/23/02. Values for the total bunched+un-bunched beam ions were obtained from the DC current transformer (DCCT). Values for the number of bunched ions were obtained from the wall current monitor (WCM). Separate values for the Blue and Yellow ring were recorded into the STAR database every minute during the run, and were retrieved for this analysis.

The average of the relative deviation of the DCCT from the WCM was determined day-by-day, and is plotted below.

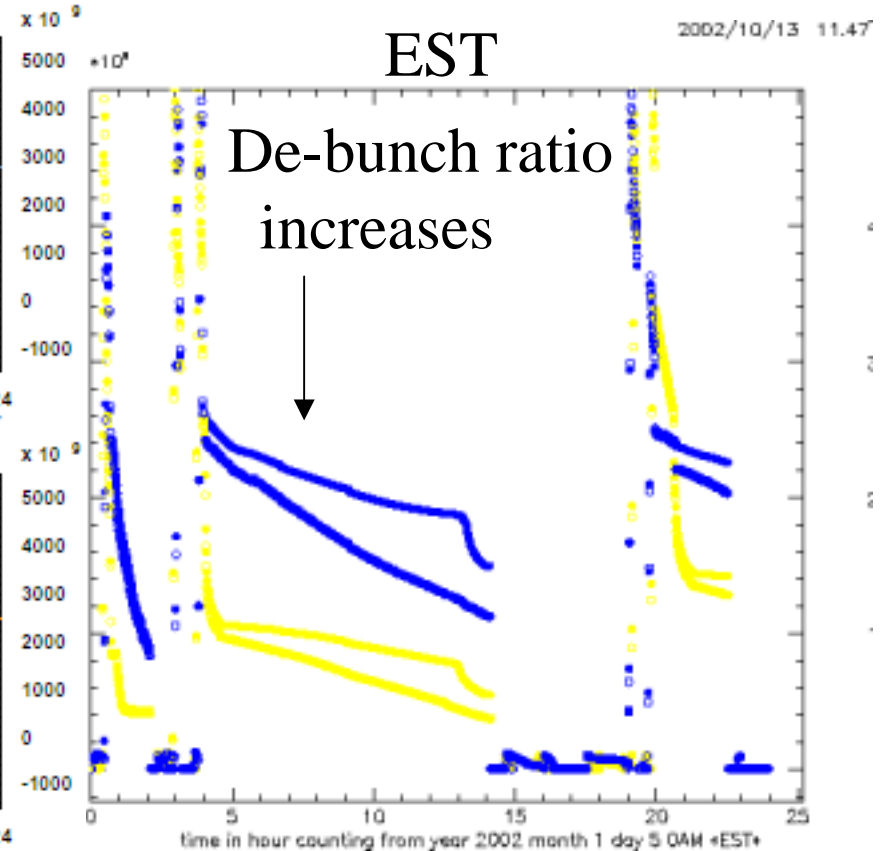
Most of the data are scattered about values reflecting offsets in the calibrations of the two devices. Significant deviations are seen in the **Yellow ring on 12/30, 12/31, 1/5, 1/6, 1/7, 1/8** and in the **Blue ring on 1/5, 1/7 and 1/8**. There may be increased background in the corresponding CNI polarimeter on those days.

1/5/02 comparison

Physics Asymmetry (1/5/02) EDT



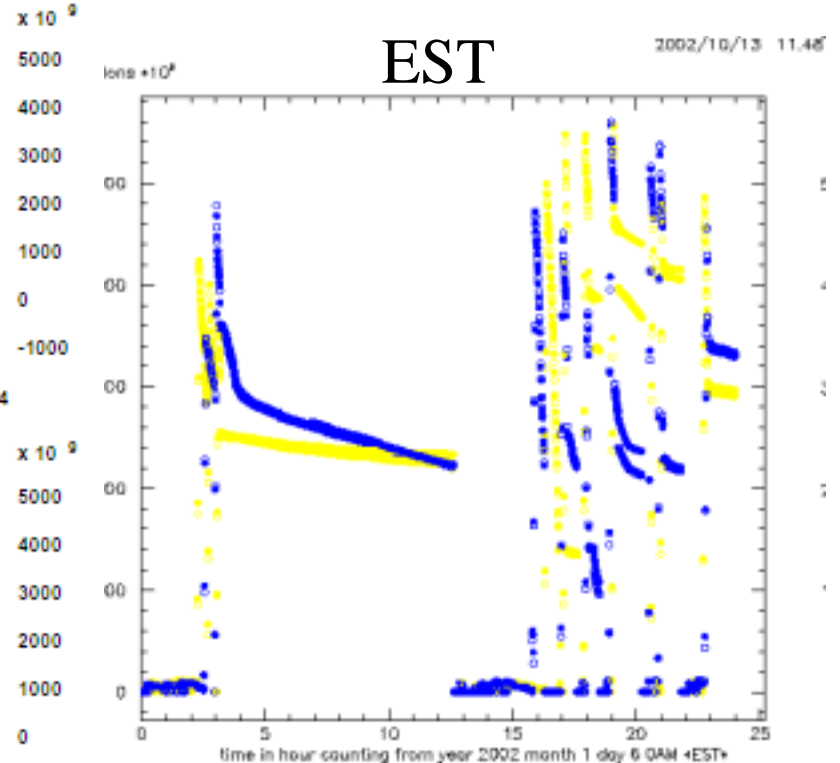
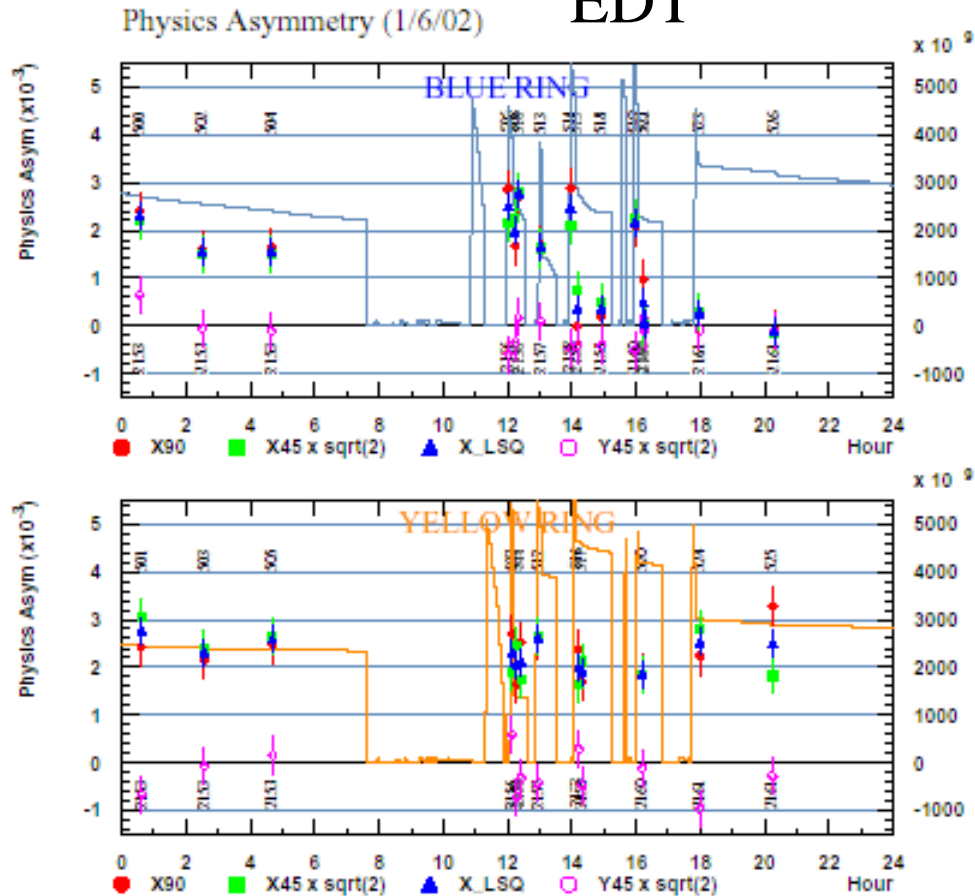
EST



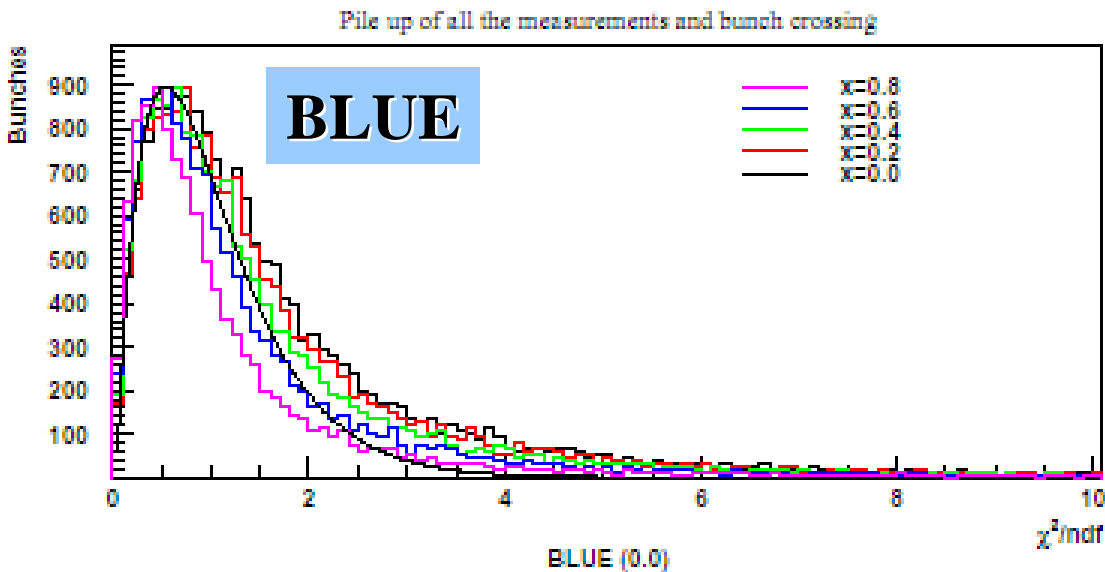
1/6/02 comparison

EDT

EST

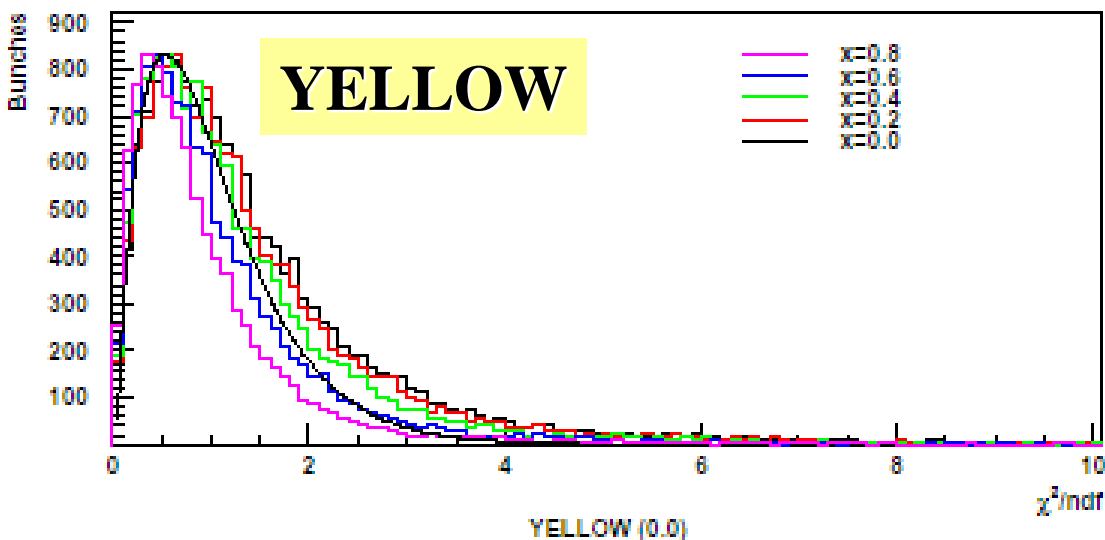


Scaled χ^2/ndf distributions



$$\chi^2 = \sum_{\text{detector}} \left(\frac{(x_i - \bar{x}_i)^2}{\sigma_{\text{stat}}^2 + \sigma_{\text{sys}}^2} \right)$$

$$= \frac{1}{(1+f^2)} \sum_{\text{detector}} \left(\frac{(x_i - \bar{x}_i)^2}{\sigma_{\text{stat}}^2} \right)$$



“f” looks to be between 0.4 and 0.6

- Distributions are normalized with the maximum contents

Scaled χ^2/ndf distributions (in log scale)

